# A b $\{$ in itio calculation of $K$ err spectra for sem if in $n$ ite system $s$ including $\mathrm{m} u$ ltiple re ections and optical interferences 

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#### Abstract

Based on Luttinger's formulation the com plex optical conductivity tensor is calculated within the fram ew ork of the spin \{polarized relativistic screened $K$ orringa $\{K$ ohn $\{R$ ostoker $m$ ethod for layered system $s$ by $m$ eans of a contour integration technique. For polar geom etry and norm al incidence ab \{initio K err spectra of $m$ ultilayer system sare then obtained by including via a $2 \quad 2 \mathrm{~m}$ atrix technique allm ultiple re ections betw een layers and optical interferences in the layers. Applications to $\operatorname{CoF}_{5}$ and $\mathrm{Pt}_{3} \mathrm{XCOP}_{5}$ on the top of a sem if in nite foc\{Pt(111) bulk substrate show good qualitative agreem ent with the experi$m$ ental spectra, but di er from those obtained by applying the com $m$ only used


two \{m edia approach.
PACS num bers: 71.15 R f, $75.50 \mathrm{Ss}, 78.20 \mathrm{Ls}, 78.66 \mathrm{Bz}$

## I. IN TRODUCTION

M agneto-opticale ects not only provide a pow erfiultool in probing the magnetic properties of solids, [1] [3] but are also of direct technological interest as phenom ena to be used for high \{ density $m$ agneto $\{$ optical recording. 园, 4] U p to now , how ever, realistic theoretical investigations were lacking, because band \{structure $m$ ethods using supercells, 目] cannot provide an adequate description of layered system $s$, for which special com putational techniques such as the spin $\{$ polarized relativistic screened K orringa $\{K$ ohn $\{R$ ostoker (SK K R) m ethod have been designed. [6[8] Furthem ore, the absonptive parts of the optical conductivity tensor as obtained from the
 since also the dissipative parts have to be know n. H ence, in supercell type calculations, besides the necessity to use the K ram ers\{ K ronig relations, one has to include also the inter\{band contributions by m eans of a sem i\{em piricald rude term. [10] O nly recently a better schem e was developed by tw o of the present authors [11], in which a contour integration is used to obtain the com plex opticalconductivity tensor asbased Luttinger's form ula, [12] which in tum includes all inter\{ and intra\{band contributions. 13] C om bining this contour integration technique $w$ th the SK K R m ethod, realistic inter\{ and intra\{layer com plex optical conductivities can be obtained for layered system s .

H aving evaluated the inter\{ and intra\{layer opticalconductivities, them agneto\{opticalk err spectra can then be calculated by using a macroscopical model such as, e.g., the two m edia approach. 14] Because the layered system contains more boundaries than just the interface between the vacuum and the surface layer, the two\{m edia approach not fully includes the dynam ics of the electrom agnetic w aves propagation in such system s. Since the pioneering w ork of Abeles in 1950, [15] several m ethods are known in the literature 16,17] to treat multiple re ections and interferences using either a $2 \quad 2 \mathrm{~m}$ atrix [18,19] or $4 \quad 4 \mathrm{~m}$ atrix 20 [22] technique. In the present paper the $m$ agneto \{opticalK err spectra of layered system $s$ are evaluated for the $m$ ost frequently used experim ental set\{up, nam ely polar geom etry and norm al incidence, by $m$ aking use of the com plex optical conductivity tensor and the $2 \quad 2 \mathrm{~m}$ atrix technique.

In Section \# the theoreticalbackground is review ed brie y. C om putational aspects are then sum $m$ arized in Section $\mathbb{T}$. In Section $\mathbb{I V}$ the tw o $m$ edia approach (Sect. $\mathbb{I V A}$ ) and the applied

2 m atrix technique (Sect. VIC) are view ed as two di erent macroscopic models of how to calculate $m$ agneto $\left\{\begin{array}{l}\text { optical } K \text { err spectra of layered system } s . \text { P articular em phasis has been put }\end{array}\right.$ in Sect. IV B on the construction of layer\{ resolved perm iltivities in term $s$ of the ( $m$ acroscopic) $m$ aterial equation $w$ ithin linear response. This construction m ethod com bined w ith the 2 $m$ atrix technique, allow s one to determ ine self\{ consistently layer\{ resolved perm ittivities, see Sect. IV C 4. A s an illustration ab \{ initio K err spectra of of tm ultilayer system s are presented and discussed in Section $V . F$ inally, in Section $V$ the $m$ ain results are sum $m$ arized.

## II. THEORETICALERAMEW ORK

## A. Luttinger's form alism

T he frequency dependent com plex optical conductivity tensor ~ (!) can be evaluated starting from the well\{known K ubo form ula and using a scalar potential description of the electric eld. 23] H ow ever, by using the equivalent 24] vector potential description of the electric eld, one ends up w tith Luttinger's form ula: 12]

$$
\begin{equation*}
\sim(!)=\frac{\sim(!) \sim(0)}{\sim!+i} ; \tag{1}
\end{equation*}
$$

w ith the current\{ current correlation function as given by 25]

$$
\begin{equation*}
\sim(!)=\frac{i \sim}{V}_{m ; n} \frac{f(n) f(m)}{\sim!+\left(_{n} \quad m\right)} J_{n m} J_{m n}: \tag{2}
\end{equation*}
$$

Here $f()$ is the Ferm i\{D irac distribution function, $m ; n$ a pair of eigenvalues of the one\{ electron $H$ am ittonian, the $J_{m n}$ are $m$ atrix elem ents of the electronic current operator $(=$ $x ; y ; z)$ and $V$ the reference (crystalline) volum e.

The positive in nitesim al implies the electrom agnetic eld to be tumed on at $t=1$ and hence describes the interaction of the system w ith its surrounding. 26] H ow ever, as can be seen from Eq. (2), can be also viewed as a nite life\{tim e broadening, whidh accounts for all scattering processes at a nite tem perature.

Luttinger's form ula (1) and Eq. (A) have several advantages over the com m only used optical conductivity tensor form ula of C allaw ay. [9] F irst of all, in contrast to the latter, Eq. [1)
sim ultaneously provides both, the absonptive and the dissipative parts of the optical conductivily tensor. H ence there is no need for using the $K$ ram ers $\{\mathrm{K}$ ronig relations in the Luttinger's form alism. On the other hand, as recently was shown [13] Luttinger's form alism accounts for both, the inter\{ and the intra\{band contribution on the sam e footing. Thus by using Eq. (1) in com bination w th Eq. (2), one does not need to include a phenom enologicalD nude term in order to sim ulate the intra\{band contribution. 5] Furtherm ore, as was also dem onstrated 13]] Eqs. (1]) and (2) can be used for calculations in the static $(!=0)$ lim it, provided the life $\{$ tim e broadening is kept nite ( $\mathrm{G}_{\mathrm{t}}$ ).

## B. C ontour integration tech $n$ ique

Instead ofevaluating the sum $s$ in the expression for the current\{ current correlation function (2) over eigenvalues of the one\{electron H am iltonian, $\sim(!)$ can be calculated by m eans of a contour integration in the com plex energy plane.

For the selection of particular contour , this technique 11] exploits the facts that w the exception of the $M$ atsubara poles $Z_{k}="_{F}+i(2 k \quad 1){ }_{T}\left(k=0 ; 1 ; 2 ;::\right.$, and $\left.T_{T}=k_{B} T\right)$, 27] in both sem i\{planes the Ferm i\{D irac distribution function of com plex argum ent $f(z)$ is analytical 25] and is a real function for complex energies $z=\| \quad i \quad j$ situated in $\{$ betw een tw o successive $M$ atsubara poles. 28] The latter property of $f(z)$, e.g., is exploited by using ${ }_{j}=2 N_{j ~ t}$, where $N_{1}$ is the num ber ofM atsubara poles included in in the upper sem i\{plane and $\mathrm{N}_{2}$ in the lower sem i\{plane. 11]

By applying the residue theorem, 边 has been shown [11] that equivalently to Eq. (2) one has

$$
\begin{aligned}
& \text { Z Z } \\
& \text { ~ }(!)=d z f(z) \sim(z+\quad ; z) \quad d z f(z) \sim(z \quad ; z)
\end{aligned}
$$

$$
\begin{align*}
& 2 i_{T}{ }_{k=N_{2}+1}^{\sim} \sim\left(z_{k}+; z_{k}\right)+\sim\left(z_{k} \quad ; \mathrm{Z}_{\mathrm{k}}\right)^{i} ; \tag{3}
\end{align*}
$$

such that
Z
where $=\sim!+i$ and the kemel

$$
\sim\left(z_{1} ; z_{2}\right)=\frac{\sim}{2 V} \operatorname{Tr}\left[\begin{array}{lll}
J & G\left(z_{1}\right) J & \left.G\left(z_{2}\right)\right] ; \tag{5}
\end{array}\right.
$$

is related to the electronic $G$ reen function $G(z)$. T he auxiliary quantity $\sim\left(z_{1} ; z_{2}\right)$ has already been used in residual resistivity calculations (! ; T = 0) of substitutionally disordered bulk system s 29] and $m$ agneto \{ transport calculations of inhom ogeneously disordered layered system s. 30] O nly recently, how ever, it has been shown, 13] that E qs. (3) \{ (5) preserve all the advantages and features of Luttinger's form alism as was m entioned already above.

In the present paper, ~ $\left(z_{1} ; z_{2}\right)$ is evaluated in term $s$ of relativistic current operators 30] and the G reen functions provided by the spin \{polarized relativistic SK K R m ethod for layered system s 目;[8]. T he optical conductivity tensor of a m ultilayer system is then given 31] by

$$
\begin{equation*}
\sim(!)=X_{p=1}^{X^{N} \quad X^{N}} \sim^{\mathrm{pq}}(!) ; \tag{6}
\end{equation*}
$$

w th $\sim^{\mathrm{pq}}(!)$ refering to either the inter\{ $(\mathrm{p} \in \mathrm{q})$ or the intra\{layer $(p=q)$ contribution to the optical conductivity tensor.

## III. COMPUTATIONALDETAILS

In addition to the num ber of M atsubara poles considered, the optical conductivity tensor depends also on the num ber of com plex energy points $n_{z}$ used in order to evaluate the energy integrals in Eqs. (3) and 4), on the num ber of $\widetilde{K}$ (points used to calculate the scattering path operators that de ne the $G$ reen functions 7] and $\sim(z \quad \sim!+i ; z)$ for a given energy $z$. Recently, the present authors have proposed two schem es to control the accuracy of these $z$ \{ and $\mathbb{K}\{$ integrations. 32]

The rst of these schem es is $m$ eant to control the accuracy of the $z\{$ integrations along each contour part by com paring the results obtained from the K onrod quadrature 33, 34], $K_{2 n_{z}+1} \sim(!)$, w ith those from the $G$ auss integration nule, $\left.G_{n_{z}} \sim(!) .35\right] O n$ a particular part of the contour ~ (!) is said to be converged, if the follow ing convergence criterion: 32]

$$
\begin{equation*}
\max \quad \mathrm{K}_{2 \mathrm{n}_{\mathrm{z}}+1} \sim \quad(!) \quad \mathrm{G}_{\mathrm{n}_{\mathrm{z}}} \sim(!) \quad \quad_{\mathrm{z}} \text {; } \tag{7}
\end{equation*}
$$

is ful lled for a given accuracy param eter ${ }_{z}$.
T he other schem e refers to the cum ulative special points $m$ ethod, 32] which perm its to perform two\{dim ensional $\widetilde{K}$ \{space integrations $w$ ith arbitrary high precision. This method exploits the arbitrariness of the special points $m$ esh origin. 36] For a given (arbitrary high) accuracy $\mathbb{K}^{\text {t }}$ the follow ing convergence criterion has to apply

$$
\begin{equation*}
\max \quad \mathrm{S}_{\mathrm{n}_{\mathrm{i}}} \sim\left(\mathrm{z}^{0} ; \mathrm{z}\right) \quad \mathrm{S}_{\mathrm{n}_{\mathrm{i} 1}} \sim\left(\mathrm{z}^{0} ; \mathrm{z}\right) \quad "_{\widetilde{k}} ; \tag{8}
\end{equation*}
$$

for any com plex energy $z$ on the contour or $z_{k} M$ atsubara pole. $H$ ere $n_{i}=2^{i+2} n_{0}\left(n_{0} 2 N\right)$ is the num ber of divisions along each prim tive translation vector in the two \{dim ensionalk \{space and $z^{0}=z+\quad, \quad z \quad$.

In the present paper, the optical conductivity tensor calculations were carried out for $\mathrm{T}=$ 300 K , using a life\{tim e broadening of $0: 048 \mathrm{R}$ yd and $\mathrm{N}_{2}=2 \mathrm{M}$ atsubara poles in the lower sem i\{plane. Because the com putation of ~ (!) does not depend on the form of the contour, 32] in the upper sem i\{plane we have accelerated the calculations by considering $\mathrm{N}_{1}=37$ M atsubara poles. The convergence criteria (7) and (8) were ful led for ${ }_{z}="_{\overparen{k}}=10{ }^{3}$ a.u. . IV.MAGNETO\{OPTICALKERREFFECT

In the case of the polarm agneto opticalk erre ect (PM O K E ), 14] the K err rotation angle

$$
\begin{equation*}
\mathrm{k}=\frac{1}{2}(+\quad) \tag{9}
\end{equation*}
$$

and the K err ellipticity

$$
\begin{equation*}
"_{K}=\frac{r_{+} r}{r_{+}+r} \tag{10}
\end{equation*}
$$

are given in term $s$ of the com plex re ectivity of the right $\{(+)$ and left\{handed (\{) circularly polarized light

$$
\begin{equation*}
\mathscr{P}=\frac{E^{(r)}}{E^{(i)}}=r \quad e^{i} \quad: \tag{11}
\end{equation*}
$$

H ere the com plex am plitude of the re ected right \{ and left\{handed circularly polarized light is denoted by $\mathrm{E}^{(\mathrm{r})}$ and that of the incident light by $\mathrm{E}^{(\mathrm{i})}$; is the phase of the com plex
re ectivity $r$ and $r=j e j$ Eqs. (G) and (10) are exact, which can be easily deduced from sim ple geom etrical argum ents. H ow ever, in order to apply these relations, one needs to m ake use of a m acroscopic m odel for the occurring re ectivities.

## A. M acroscopic m odel I: the two\{m edia approach

$T$ his sim plest and $m$ ost com $m$ only used $m$ acroscopic $m$ odel treats the $m$ ultilayer system as a hom ogeneous, anisotropic, sem i\{ in nite m edium, such that the incident light is re ected only at the boundary between the vacuum and the surface (top) layer.

In case of norm al incidence the two\{m edia approach provides an appropriate form ula for the com plex K err angle 14]

$$
\begin{equation*}
\sim_{\text {к }} \quad \text { к } \quad i^{\prime \prime}=i \frac{\mathfrak{x}_{+}}{\mathfrak{x}_{+}+\rightsquigarrow} ; \tag{12}
\end{equation*}
$$

which can be deduced from Eqs. (9) and (10) by assum ing a sm all di erence in the com plex re ectivity of the right\{ and left\{handed circularly polarized light. Because $\operatorname{Im} \sim_{x y}(!)$ usually is alm ost a hundred tim es sm aller than $\operatorname{Re} \sim_{x x}(!)$, see $R$ ef. [13], the average com plex refractive index of the right $\left\{\right.$ and left\{handed circularly polarized light is dom inated by $\sim_{x x}(!)$ and hence the follow ing direct form ula results from Eq. [12): [14]

$$
\begin{equation*}
\sim_{K} \frac{\sim_{X y}(!)}{\sim_{X X}(!)} \underset{1}{1 \quad \frac{4 i}{!} \sim_{x x}(!)} ; \tag{13}
\end{equation*}
$$

with ~ (! ) as given by Eq. (G). It should be noted that the \direct" formula in Eq. (13) was introduced by Reim and Schoenes [14] in order to extract the optical conductivity tensor elem ents $\sim_{x x}(!)$ and $\sim_{x y}(!)$ from experim entalPM OKE data.

## B.M acroscopic m odel II: layer\{ resolved perm ittivities

W ithin linear response theory 37] the Fourier transform ed m acroscopic $m$ aterialequations, 38] averaged over the reference volum e V , directly yields the total electric displacem ent

$$
\begin{equation*}
\frac{1}{V}_{v}^{Z} d^{3} r D(x ;!)=\frac{1}{V}_{v}^{Z} d^{3} r d^{Z} d^{3} r^{0} \sim\left(!; x ; x^{0}\right) E\left(x^{0} ;!\right) ; \tag{14}
\end{equation*}
$$

provided that the dielectric function $\sim\left(!; \mathbb{F} ; \mathbb{I}^{9}\right)$ and the Fourier com ponents of the electric eld $E\left(x^{0} ;!\right)$ are known.

U sing non \{ overlapping cells in con guration space (A tom ic Sphere Approxim ation (A SA), applied in the present approach), the reference volum e can be w rilten as

where $\mathrm{N}_{\mathrm{k}}$ is the num ber of atom sper layer (the sam e 2D lattige has to apply for each layer p ), $N$ the total num ber of layers and pi the volum e of the ith atom ic sphere in layer p.

A ssum ing that plane waves propagate in a layer like in a two \{dim ensional unbound hom ogeneous medium and that $\widetilde{\Sigma}_{p i}(x ;!)=\widetilde{\Sigma}_{p}(x ;!)$, the integral on the left hand side of Eq. (14) can be w ritten w thin the A SA as

$$
\begin{equation*}
d_{v}^{Z} d^{3} r \widetilde{D}(x ;!)=N_{k} X_{p=1}^{N_{p}} \widetilde{D}_{i}^{X} \quad{ }_{p i} 1+6_{k=1}^{X^{1}} \frac{(1)^{k}(k+1)}{(2 k+3)!} \frac{2}{0} n_{p} S_{p i}^{2 k} \quad \text {; } \tag{15}
\end{equation*}
$$

where $\widetilde{D}_{p}$ is the am plitude of the electric displacem ent, $\mathrm{m}_{\mathrm{p}}$ is the refraction vector,

$$
\begin{equation*}
\mathrm{n}_{\mathrm{p}}=\frac{\mathrm{q}_{p}}{\mathrm{q}_{0}} ; \tag{16}
\end{equation*}
$$

$Q_{0}$ the wave vector ( $q_{0}=2=0$ refers to the propagation constant in vacuum ) and $S_{p i}$ is the radius of the ith atom ic sphere in layer p. A ccordingly, the double integral on the right hand side of Eq. (14) reduces to

$$
\begin{align*}
& \sim^{\text {pi;qj }}\left(!; \mathrm{r}_{\boldsymbol{\prime}} \mathrm{r}^{0}\right) 1_{\mathrm{k}=1}^{\mathrm{p} ; \mathrm{q}=1} \mathrm{X}^{\mathrm{X}} \frac{(1)^{\mathrm{k}}}{(2 \mathrm{k}+1)!} \frac{2}{0} \mathrm{n}_{\mathrm{q}} \mathrm{r}^{\mathrm{O}^{2 k^{2}}} \text {; } \tag{17}
\end{align*}
$$

where $E_{q}$ is the amplitude of the electric eld in layer $q$ and $\sim^{p i ; q j}\left(!; r ; r^{0}\right)$ is the dielectric


In the case of visible light the w ave vector dependence of the perm ittivity is negligeable. [14] Therefore, after having substituted Eqs. 15) and (17) into Eq. (14), only the rst term in the pow er series expansions has to be kept, whidh im m ediately leads to

where the inter $\{(p \in q)$, intra\{layer $(p=q)$ perm ittivities are given by

It should be noted that a sim ilar result connecting the static current in layer p to the electric eld in layer $q$ is already know $n$ from electric transport theory in inhom ogeneous 39] or layered system s 30]. By using the relation $\widetilde{D}_{p}=\sim^{p}(!)$ Ep, the layer\{ resolved perm ittivities $\sim^{p}(!)$ are then solutions of the follow ing system of equations:

$$
\begin{equation*}
\sim^{p}(!) E_{p}=X_{q=1}^{X^{N}} \sim^{p q}(!) E_{q} ; \quad p=1 ;::: ; N: \tag{18}
\end{equation*}
$$

By m apping the inter\{ and intra\{layer contributions $\sim^{\mathrm{pq}}(!)$ to them icroscopically exact optical conductivity tensor ~ (! ), Eq. (G), onto the corresponding contributions of the perm ittivity tensor

$$
\begin{equation*}
\sim^{\mathrm{pq}}(!)=\frac{1}{\mathrm{~N}} \quad 1 \quad \frac{4 \mathrm{i}}{!} \sim^{\mathrm{pq}}(!) \quad ; \tag{19}
\end{equation*}
$$

one then can establish a well\{de ned $m$ acroscopical $m$ odel for the evaluation of $K$ err spectra.

$$
\mathrm{C} \cdot \mathrm{~T} \text { he } 2 \quad 2 \mathrm{~m} \text { atrix techn ique }
$$

## 1. M ultiple re ections and optical interferenœes

In contrast to the two\{m edia approach the inchusion of all optical re ections and interferences within a multilayer system assum es that each layer acts as a hom ogeneous, anisotropic $m$ edium between two boundaries and is characterized by a layer\{ resolved dielectric tensor $\sim^{p}$ ( $\mathrm{p}=1$; : : : ; N ) . 19, 19]

A s a rst step the Fresnel or characteristic equation: 40]

$$
\begin{equation*}
\mathrm{n}_{\mathrm{p}}^{2} \quad \mathrm{n}_{\mathrm{p}} \mathrm{n}_{\mathrm{p}} \quad \sim^{p}=0 \quad(;=x ; y ; z) \tag{20}
\end{equation*}
$$

has to be solved in order to determ ine the norm alm odes of the electrom agnetic waves in a particular layer $p$. 41] Then by solving the H em holtz equation for each norm alm odes, 41]

$$
\begin{equation*}
\mathrm{n}_{\mathrm{p}}^{2} \quad \mathrm{n}_{\mathrm{p}} \mathrm{n}_{\mathrm{p}} \quad \mathfrak{p} \quad \mathrm{E}_{\mathrm{p}}=0 \quad(; \quad=\mathrm{x} ; \mathrm{y} ; \mathrm{z}) ; \tag{21}
\end{equation*}
$$

the corresponding $\mathrm{E}_{\mathrm{p}}$ com ponents of the electric eld in layer p are deduced. A fter having obtained the $\mathrm{E}_{\mathrm{p}} \mathrm{s}$, the curlM axw ell equation 18,19]

$$
\begin{equation*}
\mathrm{H}_{\mathrm{p}}=\mathrm{r}_{\mathrm{p}} \quad \mathrm{E}_{\mathrm{p}} ; \tag{22}
\end{equation*}
$$

provides the amplitudes of the $m$ agnetic elds $\tilde{H}_{p}$ for each nom alm ode in layer $p$. Here the Gaussian system of units has been used, $\mathrm{r}_{\mathrm{p}}$ is the refraction vector, as given by Eq. (16), $j \mu_{p} \mathrm{n}_{\mathrm{p}}$, which in an anisotropic m edium is direction and frequency dependent. 40]
$F$ inally, continuity of the tangential com ponents of the electric and the $m$ agnetic eld at the boundary between adjacent layers leads to a set ofequations, which has to be solved recursively in order to determ ine the $m$ agneto \{optical coe cients of the layered system, such as, e.g., the surface re ectivity. If no sym m etry reduced quantities $\sim^{p}$ are used all the previous steps, Eqs. (2d) \{ (22), have to be perform ed num erically by using \{ for exam ple \{ the 22 m atrix technique of $M$ ansuripur. 18 19]

M ost frequently M OKE experim ents are perform ed in polar geom etry using norm al incidence. Therefore in the follow ing the $2 \quad 2 \mathrm{~m}$ atrix technique of M ansuripur is con ned to this particular experim ental geom etry. This reduction has the advantage that w the exception of the last step in which the surface re ectivity has to be evaluated, all the other steps can be carried out analytically.

In the case of cubic, hexagonal or tetragonal system $s$ and the orientation of the $m$ agnetization $\mathbb{M}_{p}$ pointing along the surface norm al (z\{direction), the layer\{resolved perm 歫iviy tensor is given by
 can be show $n\left\{\right.$ is proportional to the di erence $\sim_{z z}^{p} \quad{\underset{x x}{ }}_{p}^{p}$, which in tum is usually sm allenough to be neglected. If in polar geom etry the incidence is norm al,

$$
\mathrm{R}_{\mathrm{px}}=\mathrm{R}_{\mathrm{py}}=0 \text { for } \mathrm{p}=1 ;::: ; \mathrm{N} ;
$$

the characteristic equation (2G) provides four norm alm odes ofelectrom agnetic waves in a layer p :

$$
\mathrm{r}_{\mathrm{pz}}=\mathrm{P} \underset{\underset{\mathrm{xx}}{p} \underset{\mathrm{i}_{\mathrm{xy}}^{p}}{p}}{ }:
$$

T w o of these four solutions are alw ays situated in the low er half and the other two in the upper half of the complex plane. The rst two solutions, $\mathrm{R}_{\mathrm{pz}}^{(1)}$ and $\mathrm{R}_{\mathrm{pz}}^{(2)}$, correspond to a \dow nw ard" (negative $z$ \{direction) and the other two, $\mathrm{A}_{\mathrm{pz}}^{(3)}$ and $\mathrm{R}_{\mathrm{pz}}^{(4)}$, an \upward" (positive z \{direction) propagation of the electrom agnetic w aves. 18,19] These tw o di erent kinds of cases are given by

$$
\begin{align*}
& ? \mathrm{n}_{\mathrm{pz}}^{(2)}=\mathrm{p} \underset{\underset{\mathrm{Vx}}{\mathrm{p}}}{\mathrm{i} \mathrm{i}_{\mathrm{xy}}^{p}} \tag{24}
\end{align*}
$$

and

If in a given $m$ ultilayer system a particular layer $p$ is param agnetic, its perm ittivity tensor $\sim^{p}$ is again of form shown in Eq. (23), with $\sim_{x y}^{p}=0$ and $\sim_{z z}^{p}=\sim_{x x}^{p}$. In this case only two beam $s$ are propagating, nam ely those characterized by $\mathrm{n}_{\mathrm{pz}}^{(1)} \quad \mathrm{R}_{\mathrm{pz}}^{(2)}=\mathrm{P}_{\overline{\gamma_{x x}^{p}}}$ and $\mathrm{n}_{\mathrm{pz}}^{(3)} \quad \mathrm{n}_{\mathrm{pz}}^{(4)}=\mathrm{P} \frac{\nu_{\mathrm{xx}}^{p}}{}$. Furtherm ore, since the vacuum is a hom ogeneous, isotropic, sem i\{ in nite $m$ edium, in addition to $\tau_{x y}=0, \sim_{x x}=\sim_{z z}=1$.

For each solution $n_{p z}^{(k)}(k=1 ;::: ; 4)$ of the characteristic equation 20), the electric eld m ust satisfy the H elm holtz equation (21). Because not all of the equations are independent, these can be solved only for tw o com ponents of the electric eld keeping the third one arbitrary. Therefore, follow ing the strategy proposed by $M$ ansuripur, for beam $1\left(n_{p z}^{(1)}\right)$ and beam $3\left(n_{p z}^{(3)}\right)$, the corresponding $E_{p x}^{(k)}$ are chosen arbitrary, whereas forbeam $2\left(n_{p z}^{(2)}\right)$ and beam $4\left(n_{p z}^{(4)}\right)$, the $E_{p y}^{(k)}$ are arbitrary. 19, 19] For polar geom etry and norm al incidence, the solutions of the H elm holtz equation (21) are given in Table $\ddagger$ and the corresponding com ponents of the magnetic eld as obtained from Eq. (22) are listed in Table \#.

## 2. Layer resolyed re ectivity m atrix

N um bering the layers starting from the rst one on top of the substrate tow ards the surface, the surface layer has the layer index $p=N$, see $F$ ig. 1 . The 22 re ectivity m atrix $R p$ at the low er boundary $z_{p}$ of layer $p$ is given by: 18,19]

$$
\begin{aligned}
& \begin{array}{llllllll}
0 & 1 & 0 & 1 & 0 & 1 & 0 & 1
\end{array}
\end{aligned}
$$

see also the explicit discussion in the A ppendix. T he tangential com ponents of the electric and $m$ agnetic eld at a point $z_{p}^{+}$just above the boundary $z_{p}$ are then given by
where according to Tables $\mathbb{\sharp}$ and $\mathbb{Z}$,

$$
\begin{aligned}
& \begin{array}{llll}
0 & 1 & 0 & 1
\end{array}
\end{aligned}
$$

and $I$ is the 2 unit $m$ atrix.
U sing the lower boundary $z_{p} 1$ as reference plane for the four beam $s$ in layer $p \quad 1$, the tangential com ponents of the electric and $m$ agnetic eld at a point $z_{p}$ just below the boundary $z_{p}$ are of the form
where
w ith

$$
\sim_{p}^{(k)}{ }_{1}^{(k)} \mathrm{r}_{\mathrm{p}}^{(k)}{ }_{1 \mathrm{z}} \mathrm{~d}_{\mathrm{p}} 1 ; \quad \mathrm{k}=1 ;::: ; 4:
$$

In here $d_{p} \quad z_{p+1} \quad z_{p}$ is the thickness of layer $p, R_{p}^{(k)}{ }_{1 z}$ is de ned in Eqs. (24) and (25) and $q_{0}$ is the propagation constant in vacuum, se Sect. IV B.

B ased on Eqs. 27) and 29), the continuity of the tangentialcom ponents of the electric and $m$ agnetic eld on the boundary $z_{p}$ im plies that
such that by elim inating the electric eld vectors, one im $m$ ediately gets

$$
D_{p 1}\left(1+R_{p}\right)=B_{p}^{12}\left(\begin{array}{ll}
I & \left.R_{p}\right) ; ~
\end{array}\right.
$$

where

$$
\begin{equation*}
\mathrm{D}_{\mathrm{p} 1} \quad \mathrm{~B}_{\mathrm{p}}^{12}{ }_{1} \mathrm{C}_{\mathrm{p}}^{12}{ }_{1} \mathrm{C}_{\mathrm{p}}^{34}{ }_{1} \mathrm{R}_{\mathrm{p}} 1 \quad \mathrm{C}_{\mathrm{p}}^{12}{ }_{1}+\mathrm{C}_{\mathrm{p}}^{34}{ }_{1} \mathrm{R}_{\mathrm{p}}{ }_{1}{ }^{1}: \tag{31}
\end{equation*}
$$

$R_{p}$ is therefore given in term $s$ of $R_{p 1}$ by the follow ing sim ple recursion relation:

$$
\begin{equation*}
R_{p}=B_{p}^{12}+D_{p 1}{ }^{1} B_{p}^{12} \quad D_{p} 1 \quad p=1 ;::: ; N: \tag{32}
\end{equation*}
$$

In order to determ ine the re ectivity $m$ atrix $R_{N}$ of the surface layer, one has to evaluate all re ectivity $m$ atrioes $R$ for all layers below the surface layer. $T$ his requires to start the iterative procedure at the rst layer ( $p=1$ ) on top of the substrate. But in order to calculate $R_{1}$, one needs to know the 22 m atrix $\mathrm{D}_{0}$ corresponding to the substrate, see Eq. 32). This in tum, according to Eq. 31) is only the case, if the re ectivity $m$ atrix $R_{0}$ of the substrate is available. In order to achieve this, one has to form ulate the tangential com ponents of the electric and $m$ agnetic eld at $z_{1}$ by taking into account that the substrate is a sem i\{ in nite bulk $w$ thout any boundaries and hence $\mathrm{R}_{0}=0$. 18 19] Thus $\mathrm{D}_{0}=\mathrm{B}_{0}^{12}$, which according to Eq. 28) requires to specify the perm iltivity of the substrate.

## 3. Surface re ectivity $m$ atrix

In the vacuum region, $\sin œ \tau_{x x}=1, \tau_{x y}=0$, one has to deal $w$ th the superposition of only tw o beam s, nam ely that of the incident and re ected electrom agnetic w aves. These beam s are related through the surface re ectivity $m$ atrix $R_{\text {surf }}$ such that for polar geom etry and norm al incidence,
se the A ppendix. T hus the tangentialcom ponents of the electric and $m$ agnetic eld at a point $\mathrm{z}_{\mathrm{N}+1}^{+}$, nam ely just above the interface betw een the vacuum and the surface, are given by
where

A coording to Eqs. (29) and (34), the continuity of the tangential com ponents of the electric and $m$ agnetic elds at the vacuum and surface layer interface, $\mathrm{z}_{\mathrm{N}+1}=0$, can be written as

By elim inating from this system of equations the electric eld vectors, it follow s that

$$
F_{N}\left(1+R_{\text {surf }}\right)=B_{\text {vac }}^{12}+B_{\text {vac }}^{34} R_{\text {surf }} ;
$$

where

$$
\begin{equation*}
\mathrm{F}_{\mathrm{N}} \quad \mathrm{~B}_{\mathrm{N}}^{12} \quad \mathrm{C}_{\mathrm{N}}^{12} \quad \mathrm{C}_{\mathrm{N}}^{34} \mathrm{R}_{\mathrm{N}} \quad \mathrm{C}_{\mathrm{N}}^{12}+\mathrm{C}_{\mathrm{N}}^{34} \mathrm{R}_{\mathrm{N}} \quad{ }^{1} \mathrm{~A}^{1}=\mathrm{D}_{\mathrm{N}} \mathrm{~A}^{1}: \tag{36}
\end{equation*}
$$

Thus for the surface re ectivity $m$ atrix one obtains

$$
\begin{equation*}
R_{\text {surf }}=F_{N} \quad B_{\text {vac }}^{34} \quad{ }^{1} B_{\text {vac }}^{12} \quad F_{N}: \tag{37}
\end{equation*}
$$

$T$ he surface re ectivity $m$ atrix $R_{\text {surf }}$ is therefore of the form given in Eq. 33), see also A ppendix. In spherical coordinates, one im m ediately obtains the complex re ectivity of the right\{ and left\{handed circularly polarized light as

$$
x^{\mathscr{L}}=\mathfrak{x}_{\mathrm{xx}} \quad \mathfrak{x}_{\mathrm{xy}} ;
$$

which in tum determ ines the $K$ err rotation angle $k$ and ellipticity $к$, see Eqs. (9) and (10).

## 4. Selff consistent layer \{ resolyed perm ittivities

In order to calculate for a hom ogeneous, anisotropic layer $p$ the corresponding dielectric tensor (23) from the inter\{ and intra\{layer perm ittivities de ned in Eq. (19), the follow ing linear system of equations
has to be solved, see Eq. (18). H ere for $\mathrm{E}_{\mathrm{p}}$ one can take the follow ing A nsatz:
where due to Eq. 30),

By using the continuity equation of the tangential components of the electric eld at the boundaries, see Eqs. 27), 29) and (34), one then obtains the layer (resolved perm ittivities as a weighted sum of the inter\{ and intra\{ layer perm ittivities de ned in Eq. 19):

$$
\begin{align*}
& \sim_{x y}^{p} \sim_{x x}^{p} \quad q=1 \tag{38}
\end{align*}
$$

where
w ith

$$
W_{p+k}=\left(I+R_{p+k}\right) C_{p+k}^{12}+C_{p+k}^{34} R_{p+k}{ }^{1} ; \quad k=1 ;::: ; N \quad p ;
$$

and

$$
W_{p}={ }^{h} C_{p}^{12} \frac{1}{2}+C_{p}^{34} \frac{1}{2} R_{p}^{i} C_{p}^{12}+C_{p}^{34} R_{p}^{1} ; \quad k=0:
$$

Because the 22 m atrices $\mathrm{W}_{\mathrm{p}+\mathrm{k}}$ contain $\mathrm{R}_{\mathrm{p}}, \mathrm{C}_{\mathrm{p}}^{12}$ and $\mathrm{C}_{\mathrm{p}}^{34}$, which in tum depend on layer\{ resolved perm ittivities $\sim^{p}$ (! ), Eq. (38) has to be solved iteratively.

The self\{ consistent procedure can be started by putting all 2 weighting $m$ atrioes $W$ pq in Eq. 39) to unity, i.e., by neglecting the phase di erences of the electrom agnetic w aves betw een the lower and upper boundaries in eadh layer p,

$$
\begin{equation*}
\sim^{p}(!)^{(0)}=X_{q=1}^{X^{N}} \sim^{p q}(!): \tag{40}
\end{equation*}
$$

These quantities $\sim^{p}(!)^{(0)}$ can be used to calculate $R{ }_{p}^{(0)}$ in term sofE qs. 31) and (32). Im proved layer\{resolved perm ittivities follow then from Eq. 38). This terative procedure has to be repeated until the di erence in the old and new layer\{resolved perm ittivity of layer $p$ is below a num erical threshold p,

$$
\begin{equation*}
\max \sim^{\mathrm{p}}(!)^{(\mathrm{i}+1)} \quad \sim^{\mathrm{p}}(!)^{(\mathrm{i})} \quad \mathrm{p}_{\mathrm{p}} \text { : } \tag{41}
\end{equation*}
$$

## V.RESULTSAND D ISCUSSIONS

$>$ From experm ents is known that $P t$ substrates prefer an foc (111) orientation. 42] Therefore in the present contribution, the calculations for the layered system $\operatorname{cop} t_{5} \mathcal{P} t(111)$ and $P t_{3} \mathbb{C O P} t_{5} P t(111)$ have been perform ed, with ve Pt layers serving as bu er 43] to bulk foc Pt.

The Ferm i level in Eqs. (3) and (4) is that of param agnetic foc $P$ t bulk (lattioe param eter of 7.4137 a.u.), which also serves as parent lattioe, [43] i.e., no layer relaxation is considered.

## A . P aram agnetic fcc (111) Pt substrate

A s m entioned above in order to determ ine the surface re ectivity the perm ittivity tensor of the sem i\{ in nite substrate has to be evaluated. A s can be seen from F ig. . ${ }^{\text {a }}$, the xx \{elem ent of the perm ittivity tensor of the fcc(111) Pt substrate shows a rather sim ple photon energy dependence. The real part of the perm $\operatorname{lttivity~} \sim_{x x}(!)$ has a peak around 1 eV , while the im aginary part of $\sim_{x x}(!)$ exhibits an alm ost perfect hyperbolic frequency dependence. The strong decay of $\sim_{x x}(!)$ for photon energies in the vicinity of the static lim it $(!=0)$ can be easily understood in term s of the Eqs. [19) and 49), see also Ref. 13] : for ! ! 0 the realpart of $\sim_{x x}(!)$ m ust tend to $m$ inus in nity whereas the im aginary part has to decrease.

The xy \{elem ent of the perm ittivity tensor for foc\{Pt(111) is identical zero over the whole range of optical frequencies, a functionalbehavior that ofcourse does not need to be illustrated.

## B. Self\{ consistent layer \{resolved perm ittivities

In term $s$ of the substrate and the zeroth order layer\{ resolved perm ittivities, see Eq. 40), the iterative determ ination of the surface re ectivity m atrix described above, provides also self\{ consistent, layer\{ resolved perm ittivities $\underset{x x}{p}(!)$ in a very e cient $m$ anner: in less than ve trerations an accuracy of $"_{p}=10^{13}$ for each layer $p$, see Eq. 41), can be achieved.

In order to illustrate this procedure, in $F i g$. 3 the im aginary part of the relative di erence between the self\{consistent and zeroth order layer\{resolved $x x\{e l e m$ ent of the perm iltivily tensor for $\mathrm{Cop}_{5} \mathcal{P} t(111)$ w ith and w thout Pt cap layers is displayed.
$T$ his relative di erence is to be viewed as the relative error made by using according to Eq. 4G) the 22 m atrix technique w ith zeroth order layer\{resolved perm ittivities. As can be seen from F ig. 3 , this relative error is layer, frequency and system dependent. T he higher the photon energy and the bigger the layered system the less exact are the zeroth order layer\{ resolved perm iltivities. H ow ever, for relatively $s m$ all layered system $s$, the relative error $m$ ade by using only zeroth order perm ittivities is typically below $5 \%$ for $\sim_{x x}(!)$ and less than $20 \%$ for $\sim_{x y}(!) . H$ ow ever, the resulting relative error in the $K$ err rotation angle and the ellipticity as calculated by com paring the spectra corresponding to the self\{ consistent and to the zeroth order
layer\{ resolved perm ittivities, is alw ays less than $1 \%$. Therefore, Eq. 4G) can be considered as reasonably good approxím ation for layer\{resolved perm ittivities.

## C.Polar K err e ect for norm al incidence

The system s investigated in here refer to a Comono\{layer on the top of a foc $\{\mathrm{Pt}(111)$ substrate, considering also the case of three $P$ t cap layers. A s already $m$ entioned, ve $P t$ layers serve as bu er to the sem i\{ in nite host in order to ensure that the induced $m$ agnetic $m$ om ents decrease $m$ onotonously to zero into the param agnetic Pt substrate.

The ab\{initio Kerr spectra obtained from self\{consistent layer\{resolved perm ittivities by applying the 22 m atrix technique are shown in F ig. 4. U sually, in experim ents P t cap layers are deposited on top of $\mathrm{C} O$ in order to prevent the oxidation of the surface. 44] By perform ing a separate, $m$ agnetic anisotropy calculation, [43] we have found that $\operatorname{copt}(111)$ exhibits perpendicular $m$ agnetization only in the presence of $P t$ cap layers. Therefore, for the polar K err spectra of the $C o f t_{5} \mathcal{P}(111)$ system shown in F ig. 4 the polar geom etry, nam ely the perpendicular orientation of the $m$ agnetization is im posed.

A nalyzing in Fig. 4 the K err spectra of the capped and that of the uncapped system s , several di erences can be observed. The negative peak in the K err rotation angle k at 3 eV in the spectrum of $C o f t_{5} \mathcal{P} t(111)$ alm ost disappears from the spectrum in the case of the capped layered system. In the K err ellipticity the zero location at 2.8 eV observed for the uncapped system is shifted to 2.5 eV for the capped system system and sim ultaneously the infrared ( $\mathbb{R}$ ) positive peak is shrunk and $m$ oved tow ards low er photon energies. Besides these features, the sign of the ultraviolet ( $\mathrm{U} V$ ) peak in both, the K err rotation and ellipticity spectra is changed, when the Co surface layer is capped. This particular feature can also be observed in the K err spectra obtained by using the tw $o$ \{ $m$ edia approach, see $F$ ig. S. In the tw o m edia K err rotation spectrum, the negative $\mathbb{R}$ peak at 2 eV in $\operatorname{Cof}^{-1} \mathrm{t}_{5} \mathrm{t}(111)$ is shifted to about 1 eV in case of the capped system .

C om paring the spectra in F ig. 4 w ith those in F ig. 5, it is evident that the theoretical Kerr spectra depend indeed on the $m$ acrosoopic $m$ odel used to describe the propagation of electrom agnetic waves in the system. B ecause the system $s$ investigated in here arem uch sm aller
than those used in experim ents, 44,45] a strict quantitative com parison $w$ ith experim entaldata cannot be m ade. H ow ever, a qualitative com parison based on the well\{know n, general features of the Cop t experim ental K err spectra is still possible: [43] the K err rotation angle show s (a) a sm all negative $\mathbb{R}$ peak at 1.5 eV , which decreases in am plitude with decreasing C 0 thickness, and (b) a high and broad negative UV peak, which m oves from 4.1 eV to 3.9 eV for increasing C o thickness. T he K err ellipticity is characterized by (a) a shift of the zero location at 1.5 eV (pure Co m) to 3.7 eV w ith decreasing C o thickness, (b) a positive peak around 3 eV and (c) a shift of the minim um at 4.9 eV in pure Co m tow ards higher photon energies.

In the $K$ err rotation spectra of the capped system shown in $F$ ig. 4 , there is no negative $\mathbb{R}$ peak around 1.5 eV , but a negative UV exists at 5.5 eV . The K err ellipticity spectra of the capped system in F ig. 4 , has a zero location at 2.5 eV and positive peaks show up at $0.5,3.5$, 4 and 5 eV . These features suggest that in the case of $P t_{3} \mathcal{C} \circ P t_{5} P t(111)$ the $K$ err spectra obtained by applying the $2 \quad 2 \mathrm{~m}$ atrix technique are typical for Coft layered system s .

A sim ilar investigation of the $K$ err rotation spectra in $F$ ig. ${ }^{\text {G }}$, reveals that for the capped system there are two negative $\mathbb{R}$ peaks at $1,1.5 \mathrm{eV}$ and a negative $U V$ peak around $5 \mathrm{eV} . \mathrm{The}$ K err ellipticity for the capped system in $F$ ig. 回 shows a zero location at 1 eV ( 1.5 eV in case of a pure Co lm ), two positive peaks at 4 and 5 eV and a sm all negative peak around 3 eV . A ll these features $m$ ake the $K$ err spectra of $P t_{3} \mathcal{C} \circ P t_{5} \mathcal{P} t(111)$ described via the $t w o\{m$ edia approach to resemble those of a pure Colm rather than those of a Coft layered system.

P revious results obtained by applying the $2 \quad 2 \mathrm{~m}$ atrix technique using as substrate per$m$ 此ivity that of the last Pt\{layer below the C o one, 46] have show n sim ilar characteristics in the $K$ err spectra. H ence, these features cannot be ascribed to the presence of the substrate. In an other contribution, 31] it was shown that the optical conductivity of these system $s$ is dom inated by the contributions arising from the polarized $\mathrm{P} t\{$ layers. Therefore, the pure Co

Im \{like spectra obtained for $P t_{3} \mathcal{C} \circ P t_{5} P \mathrm{f}(111)$ within the tw \{ m edia approach can be seen as an indication that a layered system cannot be approxim ated by a hom ogeneous m edium in which no optical re ections or interferences occur.

## VI.SUMMARY

$W$ e have used the 22 m atrix technique for the m ost frequently used experim ental set \{up, nam ely for polar geom etry and norm al incidence. This technique allows one to account for all multiple re ections and optical interferences in a sem $i\{$ in nite layered system. The K err rotation angle and ellipticity can be directly obtained from the treratively calculated surface re ectivity $m$ atrix, which in tum can be used to determ ine layer\{resolved perm ittivities selfi consistently. For free surface of layered system s realistic ab \{initio K err spectra are obtained using the inter\{ and intra\{layer conductivities as given by Luttinger's form ula $w$ ithin the spin $\{$ polarized relativistic screened $K$ orringa $\{K$ ohn $\{\mathrm{R}$ ostoker $m$ ethod.

A com parison of the theoretical $K$ err spectra of $C o f t_{5} P t(111)$ and $P t_{3}-P o p t s t(111)$ as obtained by applying the 22 m atrix technique and the $\mathrm{tw} \circ$ \{ m edia approach indicates that the form er technique provides typical results for layered system $s$, whereas the later approach tends to generate spectra speci c for hom ogeneous m s on top of a substrate.

## ACKNOW LEDGMENTS

This work was supported by the A ustrian M inistry of Science (C ontract No. 45.451), by the H ungarian NationalScienœ Foundation (C ontract NO. OTKA T 030240 and T029813) and partially by the RTN network \Computational M agnetoelectronics" (C ontract No. HPRN \{ C T \{2000-00143).

## APPENDIX:SYMMETRY OFREFLECTIVITYMATRICES

Since for a sem i in nite substrate, $R_{0}=0, D_{0}=B_{0}^{12}$, with $B_{0}^{12}$ as given by Eq. (28), according to Eq. (32), the re ectivity $m$ atrix of the rst layer on top of the substrate is given by

$$
\mathrm{R}_{1}=\stackrel{0}{ }=\begin{array}{cc}
\mathrm{B} & 1 \\
\mathrm{x}_{1} & 0 \\
\mathrm{C} \\
\mathrm{C} \\
\mathrm{C} & \mathrm{x}_{1}^{0}
\end{array} ;
$$

where

$$
\begin{aligned}
& 8 \\
& x_{1}=\frac{\mathrm{n}_{1 \mathrm{z}}^{(1)} \mathrm{n}_{0 \mathrm{z}}^{(1)}}{\mathrm{R}_{1 \mathrm{z}}^{(1)}+\mathrm{R}_{0 \mathrm{z}}^{(1)}} \\
& : \mathrm{x}_{1}^{0}=\frac{\mathrm{n}_{1 \mathrm{z}}^{(2)} \mathrm{n}_{0 \mathrm{z}}^{(2)}}{\mathrm{R}_{1 \mathrm{z}}^{(2)}+\mathrm{R}_{0 \mathrm{z}}^{(2)}}
\end{aligned}
$$

A ssum ing that allp 1 re ectivity $m$ atrices are of this diagonal form, nam ely
by taking into account Eqs. 28) and (30), Eq. 31) im m ediately yields

$$
\begin{aligned}
& \sigma_{\mathrm{p}} \quad 1 \quad \mathrm{i} 0_{p}^{0} 1
\end{aligned}
$$

where

The re ectivity m atrix of layer $p$ as obtained from the recursion relation (32) is found to be also diagonal
where

$$
\begin{aligned}
& 8 \\
& x_{p}=\frac{\mathrm{R}_{\mathrm{pz}}^{(1)}{\tilde{\sigma_{p}}}_{1}^{(1)}}{\mathrm{R}_{\mathrm{pz}}^{(1)}+\sigma_{\mathrm{p}}} 1
\end{aligned} ;
$$

i.e., all the layer\{ resolved re ectivity m atrioes $R_{j}(j=1 ;:: ; N)$ are diagonalm atrices as was anticipated in Eq. 26).

In term $s$ of the diagonal re ectivity $m$ atrix of the surface layer $R_{N}$, and $A$ and $B_{N}^{12}$ as given by Eq. 28), Eq. (36) reduces to
where

$$
\begin{aligned}
& \stackrel{8}{\gtrless} \tilde{f}_{\mathrm{N}}=\sigma_{\mathrm{N}}^{0} \quad \sigma_{\mathrm{N}} \\
& \vdots \\
& f_{\mathrm{N}}^{0}=d_{\mathrm{N}}^{0}+\sigma_{\mathrm{N}}
\end{aligned}
$$

By using $F_{N}$ together w th the $m$ atrices de ned in Eq. (35) in Eq. (37), the resulting surface re ectivity $m$ atrix is of the form anticipated in Eq. (33), i.e.

$$
\begin{aligned}
& 0 \quad 1
\end{aligned}
$$

where

$$
\begin{aligned}
& 8 \\
& \Im_{x X}=\frac{f_{N}^{2}+f_{N}^{Q} 4}{f_{N}^{2} f_{N}^{@ R}+4 f_{N}^{0} \quad 1}: \\
& \mathfrak{x}_{x y}=4 i \frac{f_{N}}{f_{N}^{2}} f_{N}^{(Q)}+4 f_{N}^{0} \quad 1
\end{aligned}
$$

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TABLES

| k | 1 | 2 | 3 | 4 |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{E}_{\mathrm{px}}^{(k)}$ | arbitrary | $\mathrm{iE}_{\mathrm{py}}{ }^{(2)}$ | arbitrary | $\mathrm{iF}_{\mathrm{py}}{ }^{(4)}$ |
| $\mathrm{E}_{\mathrm{py}}^{(k)}$ | $\mathrm{iF}_{\mathrm{px}}^{(1)}$ | anbitrary | $\mathrm{iF}_{\mathrm{px}}^{(3)}$ | arbitrary |
| $\mathrm{E}_{\mathrm{pz}}^{(k)}$ | 0 | 0 | 0 | 0 |

TABLE I. Solutions of the H elm holtz equation 21) for polar geom etry and nom al incidence neglecting the di erence in the diagonalelem ents of the layer\{ resolved perm ittivity. $\mathrm{E}_{\mathrm{p}}{ }^{(\mathrm{k})}$ is the am plitude of the electric eld in layer $p$ for beam $k$.

| k | 1 | 2 | 3 | 4 |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{H}_{\mathrm{px}}^{(\mathrm{k})}$ |  | $\mathrm{E}_{\mathrm{py}}^{(2)} \mathrm{P} \bar{\sim}_{\overline{x x}}^{p} \mathrm{i}_{\sim_{x y}^{p}}^{p}$ |  |  |
| $\mathrm{H}_{\mathrm{py}}^{(\mathrm{k})}$ | $\mathrm{Emx}_{\mathrm{px}}^{(1)} \mathrm{P} \overline{\sim_{x x}^{p}+i i_{x y}^{p}}$ |  | $\mathrm{E}_{\mathrm{px}}^{(3)} \mathrm{P} \overline{\sim_{x x}+i \tau_{x y}^{p}}$ |  |
| $\mathrm{H}_{\mathrm{pz}}^{(\mathrm{k})}$ | 0 | 0 | 0 | 0 |

TA B LE II. Solutions of the curlM axw ell equation (22) for polar geom etry and norm al incidence neglecting the di erence in the diagonal elem ents of the layer\{resolved perm ittivity $\mathrm{p} . \mathrm{H}_{\mathrm{p}}^{(\mathrm{k})}$ is the am plitude of the $m$ agnetic eld in layer $p$ for beam $k$.


FIG.1. Them acroscopic $m$ odel used for a layered system $w$ ith in the 22 m atrix technique for polar geom etry and norm al incidence. The $x$ axis is perpendicular to the plane of the gure, $\mathrm{of}^{(\mathrm{i})}$ is the incident and $\mathbb{G}^{(r)}$ is the re ected wave vector. $M$ denotes the total spontaneous $m$ agnetization of the system .


FIG.2. The perm ittivity for foc (111) $\{$ Pt bulk as a function of the photon energy ! . The real part of the perm iltivity is denoted by full circles, the im aginary part by open circles.


FIG.3. Im aginary part of the relative di erence between the self\{consistent and zeroth order layer\{resolved xx\{elem ent of the perm ittivity tensor as a function of the photon energy ! for foc
 correspond to the nst, squares to the second and diam onds to the third Pt layer on top of (under) the C o layer (stars). O pen triangles down (up) denote the rst (second) Pt layer data on top of a param agnetic fec\{P t(111) substrate.


F IG . 4. Them agneto optical K err rotation angle $\mathrm{k}(!)$ and ellipticity $\mathrm{k}(!)$ for polar geom etry and norm al incidence as a function of the photon energy! obtained by applying the $2 \quad 2 \mathrm{~m}$ atrix technique for the self\{ consistent layer\{ resolved perm ittivities of fic $C$ of $t_{5} \mathcal{P} t(111)$ (open circles) and $\mathrm{Pt}_{3} \mathrm{C} \circ \mathrm{P} \mathrm{t}_{5} \mathrm{P} \mathrm{t}$ (111) (full circles).




